TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

T6L87

Gate Driver for TFT LCD Panels

The T6L87 is a 256-channel output gate driver for TFT LCD panels. This device accepts external input of the panel drive voltage, allowing you to change the low-level output voltage. Thus, this device can be used for various TFT LCD panel drive systems.

Features

• LCD drive output pins : 256 pins

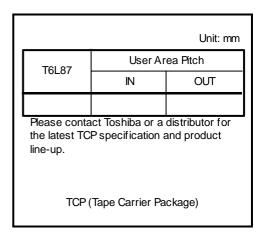
• LCD drive voltage : max VEE + 40 V

• Data transfer method : Bidirectional shift register

Operating temperature: -20 to 75°C
 Package: TCP / COF

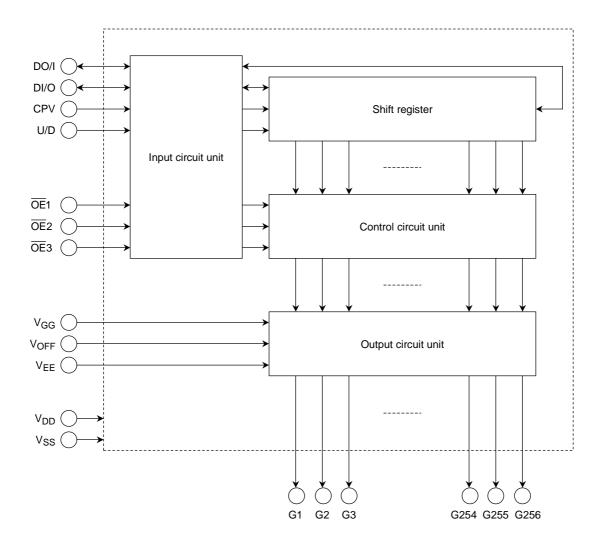
Features

• Module for PC monitor



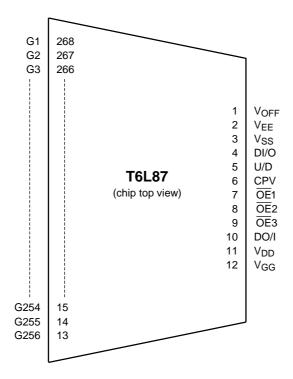


Block Diagram



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Pin Assignment



The above diagram shows the device's pin configuration only and does not necessarily correspond to the pad layout on the chip. Please contact Toshiba or our distributors for the latest TCP / COF specification.

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Pin Function

Pin Name	I/O	Function						
		Vertical shift data I/O pins These pins are used to input and output shift data. These pins are switched between input and output by setting the U/D pin as shown below.						
			U/D	DI/O	DO/I	1		
D1/0			Н	Input	Output			
DI/O DO/I	I/O		L	Output	Input			
		This pin is is latched When set for When two	When set for input This pin is used to feed data into the shift registers at the first stage of the LCD driver. The data is latched into the shift registers at the rising edge of CPV. When set for output When two or more T6L87s are cascaded, this pin outputs the data to be fed into the next stage. This data changes state synchronously with the falling edge of CPV.					
U/D	ı	This pin sp The shift ro Whe U/D Whe U/D	Transfer direction select pin This pin specifies the direction in which data is transferred through the shift registers. The shift register data is shifted synchronously with each rising edge of CPV as follows: When U/D is high, data is shifted in the direction $U/D = \text{``H''}: G1 \to G2 \to G3 \to G4 \to \cdots \to G256$ When U / D is low, the direction is reversed to give $U/D = \text{``L''}: G256 \to G255 \to G254 \to G253 \to \cdots \to G1$ The voltage applied to this pin must be a DC-level voltage that is either high (V _{DD}) or low (V _{SS}).					
CPV	I	This is the	Vertical shift clock This is the shift clock for the shift registers. Data is shifted through the shift registers synchronously with the rising edge of CPV.					
OE1 to OE3	I	Output enable pins These signals control the data appearing at the LCD panel drive pins (G1 through G256). $\overline{\text{OE}}$ doesn't synchronize with the CPU. The V _{OFF} voltage is output when $\overline{\text{OE}}$ 1 to $\overline{\text{OE}}$ 3 are high; normal shift data is output when $\overline{\text{OE}}$ 1 to $\overline{\text{OE}}$ 3 are low.						
G1 to G256	0	LCD panel drive pins These pins output the shift register data or the voltage applied to V _{GG} or V _{OFF} depending on the control signals \overline{OE} 1 to \overline{OE} 3.						
V _{GG}	_	Power supply	Power supply for LCD drive					
V _{OFF}	_	Analog reference voltage These pins accept as their input the OFF level at the LCD panel drive pins (G1 through G256).						
V _{EE}	_	Power supply for LCD drive						
V _{DD}	_	Power supply	Power supply for the internal logic					
V _{SS}	_	Power supply	Power supply for the internal logic					

Device Operation (see timing diagram)

(1) Shift data transfer method

U/D Pin	Shift Data		Data Transfer Method
	Input	Output	Data Hansier Wethou
Н	DI/O	DO/I	$G1 \rightarrow G2 \rightarrow G3 \rightarrow G4 \rightarrow \cdots \rightarrow G256$
L	DO/I	DI/O	$G256 \rightarrow G255 \rightarrow G254 \rightarrow \cdots \rightarrow G1$

The input data (DI/O or DO/I) is latched into the internal register synchronously with the rising edge of the shift clock CPV. At the same time that the data is shifted to the next register at the next rise of CPV, new vertical shift data is latched into.

In the output operation, the data in the last shift register (G256 or G1) is output synchronously with the falling edge of CPV. (The output high voltage is the VDD level; the output low voltage is the VSS level.)

(2) LCD panel drive outputs

The LCD panel drive outputs are controlled by $\overline{OE}1$ to $\overline{OE}3$ as shown below.

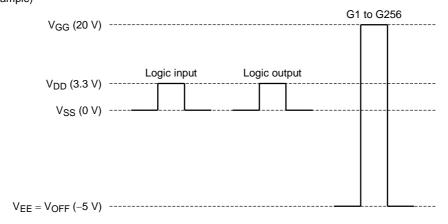
Output Enghlo Bin	LCD Panel Drive Outputs	- Output	
Output Enable Pin	LCD Panel Drive Pins Controller by OE		
OE1 = "H"	G1, G4, G7,G250, G253, G256		
ŌE2 = "H"	G2, G5, G8,G251, G254	V _{OFF}	
ŌE3 = "H"	G3, G6, G9,G252, G255		
ŌE1 = "L"	G1, G4, G7,G250, G253, G256		
ŌE2 = "L"	G2, G5, G8,G251, G254	Normal data output	
ŌE3 = "L"	G3, G6, G9,G252, G255		

(3) Voltage setting

The VOFF level, which sets the LCD panel drive's output low level, can take on any value between VEE to $V_{\rm EE}$ + 6 V. Negative voltage output is also the same as the above.

$$\begin{aligned} &V_{GG}-V_{OFF}=35~V\\ &V_{OFF}-V_{EE}=0~to~6~V\\ &V_{GG}-V_{SS}=10~to~25~V \end{aligned}$$

(Example)

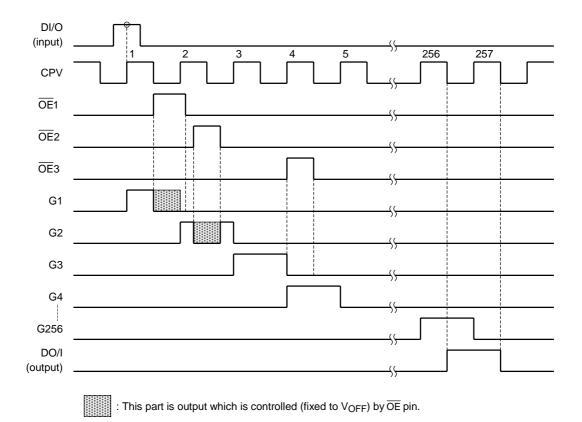


The logic input here means input pins DI/O, DO/I, CPV and $\overline{OE}1$ to $\overline{OE}3$. Make sure that the voltage applied to the U/D pin is a high (= VDD) or low (= VSS) DC-level voltage.

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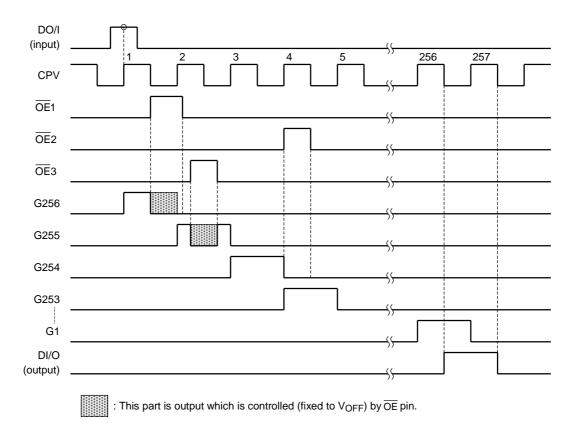
Timing Diagram 1

● UP mode (U/D = high)



Timing Diagram 2

● DOWN mode (U/D = low)



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Absolute Maximum Ratings (V_{SS} = 0 V)

Parameter	Symbol	Rating	Unit	
Supply voltage (1)	V_{DD}	-0.3 to 6.0		
Supply voltage (2)	V_{GG}	-0.3 to 42.0		
Supply voltage (3)	V _{EE}	-20.0 to 0.3	V	
Supply voltage (4)	V _{OFF}	V _{EE} - 0.3 ~V _{GG} + 0.3		
Supply voltage (5)	V _{GG} – V _{EE}	-0.3 to 42.0		
Input voltage	V _{IN}	-0.3 to V _{DD} + 0.3	V	
Storage temperature	age temperature T _{stg} -55 to 125		°C	

Recommended Operating Conditions (VSS = 0 V)

Parameter	Symbol	Rating	Unit	
Supply voltage (1)	V_{DD}	2.7 to 3.6		
Supply voltage (2)	V_{GG}	10 to 35		
Supply voltage (3)	V _{EE}	−15 to −5	V	
Supply voltage (4)	V _{OFF} – V _{EE}	0 to 6		
Supply voltage (5)	V _{GG} – V _{EE}	17 to 40		
Operating temperature	T _{opr}	-20 to 75	°C	
Operating frequency	f _{CPV}	DC to 100	kHz	
Output Load capacitance	CL	300 (max)	pF/PIN	

Electrical Characteristics

DC Characteristics

(V_{GG} - V_{EE} = 30 to 40 V, V_{DD} = 2.7 to 3.6 V, V_{SS} = 0 V, Ta = -20 to 75°C)

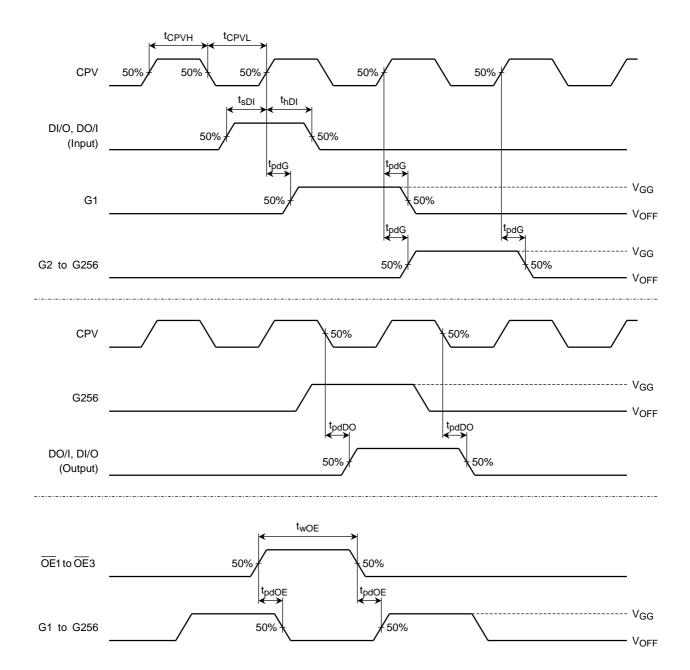
Parameter		Symbol	Test circuit	Test Condition	Min	Max	Unit	Relevant
Input voltage	Low Level	V _{IL}		_	V _{SS}	$\begin{array}{c} 0.2 \times \\ V_{DD} \end{array}$	V	(Note)
input voitage	High Level	V _{IH}		_	0.8 × V _{DD}	V _{DD}	V	(Note)
Output voltage	Low Level	V _{OL}		I _{OL} = 40 μA	V _{SS}	V _{SS} + 0.4	V	DI/O, DO/I
Output voltage	High Level	V _{OH}		I _{OH} = -40 μA	V _{DD} – 0.4	V _{DD}		
Output resistance	Low Level	R _{OL}		$V_{OUT} = V_{EE} + 0.5 V$		1000	Ω	G1 to
	High Level	R _{OH}		V _{OUT} = V _{GG} - 0.5 V	_	1000	5.2	G256
Input leakage current		I _{IN}		_	-5	5	μΑ	(Note)
Current consumption (1)		I _{GG}		OE = "L", non-load	_	20		V_{GG}
Current consumption (2)		I _{DD}	_	OE = "L"	_	15	μΑ	V _{DD}
Current consumption (3)		I _{EE}		OE = "L"	_	10		V _{EE}

Note : These input pins include DI/O, DO/I, CPV, $\overline{\text{OE}}1$ to $\overline{\text{OE}}3$

AC Characteristics

$(V_{GG} - V_{EE} = 30 \text{ to } 40 \text{ V}, V_{DD} = 2.7 \text{ to } 3.6 \text{ V}, V_{SS} = 0 \text{ V}, Ta = -20 \text{ to } 75^{\circ}\text{C})$

Parameter	Symbol	Test circuit	Test Condition	Min	Max	Unit
Clock frequency	t _{CPV}	_	_	_	100	kHz
CPV pulse width (H)	tCPVH	_	_	4	_	μS
CPV pulse width (L)	tCPVL	_	_	4	_	μS
Data set-up time	t _{sDI}	_	_	200	_	ns
Data hold time	t _{hDI}	_	_	200	_	ns
OE enable time	t _{wOE}	_	_	1	_	μS
Output delay time (1)	t _{pdDO}	_	C _L = 50 pF	_	800	
Output delay time (2)	t _{pdG}	_	C _L = 300 pF	_	800	ns
Output delay time (3)	t _{pd} OE	_	C _L = 300 pF		800	

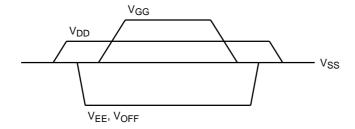


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Power Supply Sequence

Turn power on in the order VDD \rightarrow VEE. VOFF \rightarrow Input signal \rightarrow VGG Turn power off in th reverse order.



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